

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10776789	BEDNASZ ET AL.
	Examiner	Art Unit
	Pan, Yuwen	2618

SEARCHED

Class	Subclass	Date	Examiner
455	67.11, 67.14	1/16/08	YP
343	703, 702	1/16/08	YP

SEARCH NOTES

Search Notes	Date	Examiner
EAST text search	1/16/08	YP

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
455	67.14	10/15/08	YP

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